

# Thermodynamics for the preparation of SiC-C nano-composites by chemical vapour deposition

Y. WANG, M. SASAKI, T. GOTO, T. HIRAI

*Institute for Materials Research, Tohoku University, Sendai 980, Japan*

SiC-C nano-composites covering every possible combination of carbon and SiC were prepared by chemical vapour deposition. The specific compositions of the deposits were controlled by changing the Si/C molar ratio in the source gases at deposition temperatures ( $T_{\text{dep}}$ ) of 1673 to 1873 K and total gas pressures ( $P_{\text{tot}}$ ) of 6.7 to 40 kPa using the  $\text{SiCl}_4\text{-C}_3\text{H}_8\text{-H}_2$  system. The prediction, based on the thermodynamic calculation on composition, morphology and deposition rate, was compared with experimental results. The optimal deposition conditions predicted by the calculations were nearly in agreement with the experimental results.

## 1. Introduction

In recent years the development of materials which can be utilized under severe temperature conditions, such as experienced in aerospace and nuclear fusion technologies, has been undertaken. One of the approaches in this development is the preparation of "nano-composites" in which a second phase of nanometre size is dispersed in the matrix. Among these, one material receiving considerable attention is the so-called "functionally gradient material" [1, 2], in which the material properties are continuously changed by gradually varying the dispersion-to-matrix ratio from one surface of the material to the other surface. Among these "functionally gradient materials", that consisting of silicon carbide (SiC) and carbon (C) is being examined as a thermal barrier in a space shuttle [2, 3] due to its excellent oxidation resistance and good thermal shock resistance.

Chemical vapour deposition (CVD) is an effective technique in fabricating nano-composites through a co-deposition process using multi-component gas reactions [4, 5]. The main advantage of the CVD technique is the ease with which the composition and microstructure of the deposited materials can be controlled.

There have been several publications [6-10] on the preparation of SiC-C nano-composites by CVD. Yajima and Hirai [6] and Marinković *et al.* [7] prepared carbon (pyrolytic carbon) containing about 5 mol % SiC using  $\text{SiCl}_4\text{-C}_3\text{H}_8$  and  $\text{SiCl}_4\text{-CH}_4$ , respectively. Yajima and Hirai [8] revealed the size of the dispersed-SiC phase, through TEM observations, to be about 10 to 100 nm.

An improvement in the oxidation resistance has been reported when a small amount of SiC (< 5 mol %) is combined with the carbon matrix by CVD [8]. The CVD SiC-C containing a trace of carbon is shown to be more resistant to abrasion than CVD SiC [9]. Kaae and Gulden [10] prepared SiC-C nano-composite particles containing 55 to 95 mol % C in a fluidized bed furnace using the  $\text{CH}_3\text{SiCl}_3\text{-C}_3\text{H}_8\text{-He}$  system and

reported that their Young's modulus and fracture strength increased with increasing SiC content.

In previous reports, the composition (C/(SiC + C)) in the CVD SiC-C was limited to a narrow range, for example, 95 to 100 mol % C in the  $\text{SiCl}_4\text{-C}_3\text{H}_8$  [6] and  $\text{SiCl}_4\text{-CH}_4$  [7] systems, 0 to 45 mol % C in the  $\text{SiCl}_4\text{-C}_3\text{H}_8\text{-H}_2$  system [11], a distinct value of 30 and 60 mol % C in  $\text{SiCl}_4\text{-CCl}_4\text{-H}_2$  system [12] and 0 to 72 mol % C in the  $(\text{CH}_3)_x\text{SiCl}_{4-x}\text{-CH}_4$  system [13]. Thus, the preparation of SiC-C nano-composite with its composition (C/(SiC + C)) controlled over the entire range has not yet been attempted.

In the present work, as the first step in the development of SiC-C functionally gradient nano-composites, the CVD technique was used to prepare SiC-C nano-composite over all composition ranges. The relationships between deposition conditions and properties of deposited materials were thermodynamically investigated and the optimal deposition conditions are shown.

## 2. Experimental procedure

### 2.1. Sample preparation

The experimental set-up is illustrated in Fig. 1. The graphite substrate (40 mm × 12 mm × 2 mm) was heated using an electric current.  $\text{SiCl}_4$  in liquid form and  $\text{C}_3\text{H}_8$  and  $\text{H}_2$  gases were used as source materials. The deposition temperature ( $T_{\text{dep}}$ ) was selected between 1673 and 1873 K. Previous work [11] has shown that no deposits are obtainable below 1500 K for kinetic reasons and furthermore deposits obtained above 1900 K tend to be porous due to homogenous

TABLE I CVD conditions

Deposition temperature, $T_{\text{dep}}$ (K)	1673, 1773, 1873
Total gas pressure, $P_{\text{tot}}$ (kPa)	6.7, 13.3, 40
Gas flow rate ( $10^{-6} \text{ m}^3 \text{ sec}^{-1}$ ): $\text{H}_2$	0 to 11.7
$\text{SiCl}_4$	0 to 3.9
$\text{C}_3\text{H}_8$	0.67
Si to C ratio in source gas, $m_{\text{Si/C}}$	0 to 1.9
Deposition time, $t_{\text{dep}}$ (ksec)	3.6

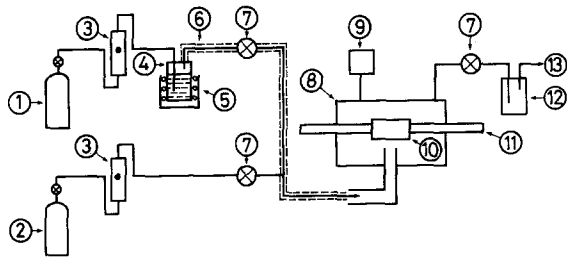


Figure 1 Schematic diagram of deposition apparatus. (1) H<sub>2</sub> gas, (2) C<sub>3</sub>H<sub>8</sub> gas, (3) flow meter, (4) SiCl<sub>4</sub> reservoir, (5) constant temperature bath, (6) ribbon heater, (7) pressure regulator, (8) reaction chamber, (9) manometer, (10) graphite substrate, (11) electrode, (12) cold trap, (13) rotary pump.

reaction in the gas phase. The total gas pressure ( $P_{\text{tot}}$ ) ranged from 6.7 to 40 kPa. The SiCl<sub>4</sub> reservoir was kept at 293 K and its vapour was carried into the furnace by bubbling hydrogen carrier gas. The SiCl<sub>4</sub> vapour flow rate was controlled by the hydrogen carrier gas flow rate. The C<sub>3</sub>H<sub>8</sub> gas flow rate was kept constant. The molar ratio of silicon to carbon in the source gas ( $m_{\text{Si/C}}$ ) ranged from 0 to 1.9. The deposition conditions are shown in Table I.

## 2.2. Characterization

The free-carbon contents of the deposits were determined by chemical analysis in which powdered samples were burnt in oxygen at 1073 K and the CO<sub>2</sub> gas formed was titrated by coulometry. The structure of the deposits was examined using an X-ray diffractometer (Rigaku: RAD-IIB), and their morphologies were observed by scanning electron microscopy (SEM) (Akashi: Alpha-30 W).

## 2.3. Thermodynamic calculations

The computer code SOLGASMIX-PV [14] was used to calculate the partial pressures of gas species and the amount of solid species in the equilibrium state. Forty-four gas species and three solid species considered in the present calculations are listed in Table II. These thermodynamic data were taken from JANAF Thermochemical Tables [15]. The theoretical deposition efficiency for carbon or silicon is given by Equation 1

$$\eta_i = \frac{a_i(s)}{a_i(g)} \quad (1)$$

where  $\eta_i$  is the deposition efficiency of atom  $i$ ,  $a_i(s)$  and  $a_i(g)$  are the total amount of atom  $i$  in the solid and gas phases, respectively.

TABLE II Species considered in SiCl<sub>4</sub>-C<sub>3</sub>H<sub>8</sub>-H<sub>2</sub> system

Equilibrium gas species					
SiC	C	Si	H <sub>2</sub>	Cl <sub>2</sub>	Si <sub>2</sub>
Si <sub>3</sub>	C <sub>2</sub>	C <sub>3</sub>	Si <sub>2</sub> C	Si <sub>2</sub> Cl <sub>2</sub>	SiH
SiH <sub>4</sub>	CH	CH <sub>2</sub>	CH <sub>3</sub>	CH <sub>4</sub>	C <sub>2</sub> H
C <sub>2</sub> H <sub>2</sub>	C <sub>2</sub> H <sub>4</sub>	Si(CH <sub>3</sub> ) <sub>4</sub>	SiCl	SiCl <sub>2</sub>	SiCl <sub>3</sub>
SiCl <sub>4</sub>	CCl	CCl <sub>2</sub>	CCl <sub>3</sub>	CCl <sub>4</sub>	C <sub>2</sub> Cl
C <sub>2</sub> Cl <sub>4</sub>	C <sub>2</sub> Cl <sub>6</sub>	HCl	CHCl	CHCl <sub>3</sub>	CH <sub>2</sub> Cl <sub>2</sub>
CH <sub>3</sub> Cl	C <sub>2</sub> HCl	SiH <sub>3</sub> Cl	SiH <sub>2</sub> Cl <sub>2</sub>	SiHCl <sub>3</sub>	SiCl <sub>3</sub> CH <sub>3</sub>
H	Cl				
Equilibrium condensed phases					
Si	SiC	C			

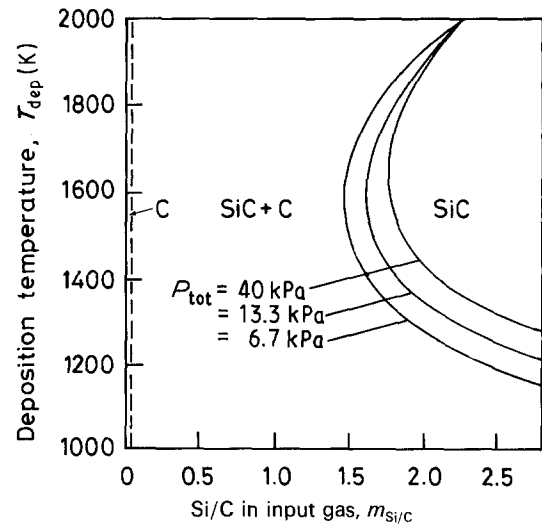


Figure 2 Calculated CVD phase diagram of the SiCl<sub>4</sub>-C<sub>3</sub>H<sub>8</sub>-H<sub>2</sub> system.

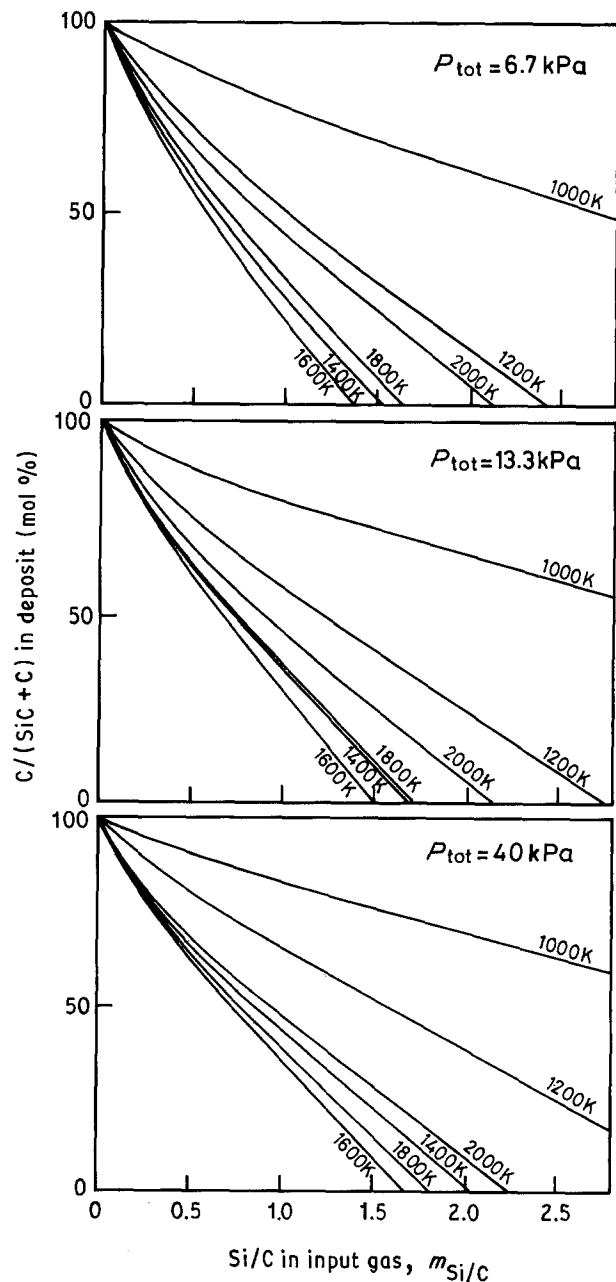


Figure 3 Relationship between calculated compositions and  $m_{\text{Si/C}}$ .

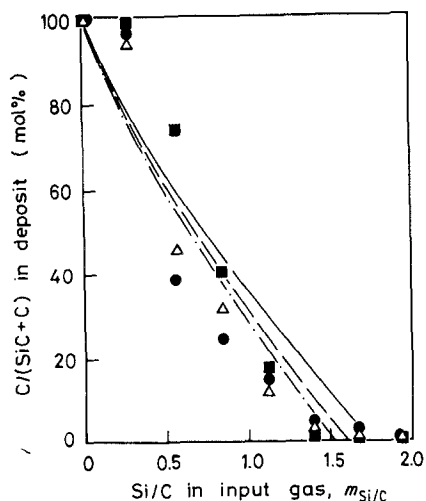


Figure 4 Comparison between calculated (lines) and experimental (points) compositions ( $T_{\text{dep}} = 1673 \text{ K}$ ).  $P_{\text{tot}}$  (kPa): (---), (●) 6.7; (-.-), ( $\Delta$ ) 13.3; (—), ( $\blacksquare$ ) 40.

### 3. Results and discussion

#### 3.1. Preparation of CVD SiC-C

Fig. 2 shows the calculated CVD phase diagram of the  $\text{SiCl}_4\text{-C}_3\text{H}_8\text{-H}_2$  system. The calculation predicts a wide range of deposition conditions for the formation of C + SiC. The SiC single-phase region appears at  $m_{\text{Si/C}} > 1.5$ . A higher  $m_{\text{Si/C}}$  is required to obtain SiC single-phase as  $P_{\text{tot}}$  increases. The SiC single-phase region is widest when  $T_{\text{dep}} = 1600 \text{ K}$ . No deposition of free silicon is predicted even at  $m_{\text{Si/C}} > 1$ .

Fig. 3 shows the calculated relationship between  $m_{\text{Si/C}}$  and the C/(SiC + C) composition in the deposits. All compositions between 0% and 100% can be achieved by controlling  $m_{\text{Si/C}}$  between 0 and 0.28 in the  $T_{\text{dep}}$  range from 1400 to 2000 K. As clearly seen from Fig. 3, the choice of  $T_{\text{dep}} = 1400$  to 1800 K is most suitable because the deviation of composition with  $T_{\text{dep}}$  is minimal.

The calculated relationships between the composition and  $m_{\text{Si/C}}$  were compared with the experimental results as shown in Figs 4 to 6. The calculations are in good agreement with the experimental results. The difference between the calculations and experiments decreased with increasing  $T_{\text{dep}}$ . This result suggests

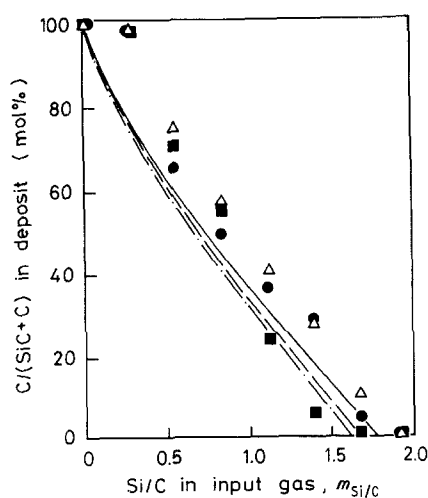


Figure 5 Comparison between calculated (lines) and experimental (points) compositions ( $T_{\text{dep}} = 1773 \text{ K}$ ).  $P_{\text{tot}}$ : see Fig. 4.

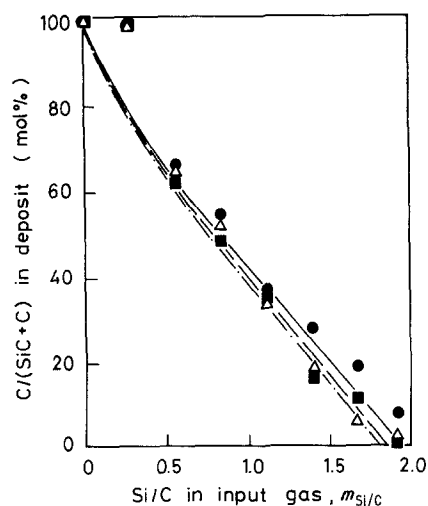


Figure 6 Comparison between calculated (lines) and experimental (points) compositions ( $T_{\text{dep}} = 1873 \text{ K}$ ).  $P_{\text{tot}}$ : see Fig. 4.

that the formation of SiC-C composites takes place closer to the equilibrium state when  $T_{\text{dep}}$  is higher.

However, when  $m_{\text{Si/C}}$  was 0.28, the experimentally obtained carbon contents consistently exceeded the calculated results at every  $T_{\text{dep}}$  and  $P_{\text{tot}}$ . Marinković *et al.* [7] and Hirai [16] reported that the presence of  $\text{SiCl}_4$  vapour in the gas phase can significantly accelerate the deposition of carbon; however, the reason for this was not known. Figs 4 to 6 also show that the single-phase region of SiC shifted to a higher  $m_{\text{Si/C}}$  with increasing  $T_{\text{dep}}$ . This tendency is in good agreement with the calculated predictions shown in Fig. 2.

Fig. 7 shows the effect of  $T_{\text{dep}}$  on the theoretical deposition efficiencies of silicon and carbon atoms. The calculation shows that the theoretical deposition efficiency of the carbon atom is more than 80% in the  $T_{\text{dep}}$  range from 1000 to 2000 K, and that of the silicon atom reaches a maximum around  $T_{\text{dep}} = 1600 \text{ K}$ . All silicon atoms react with carbon atoms to form SiC as shown in Fig. 2.

The relationship between  $T_{\text{dep}}$  and the equilibrium partial pressure of various gas species is presented in Fig. 8. The most volatile gas species containing silicon atoms changes from  $\text{SiCl}_4$  to  $\text{SiCl}_3$  to  $\text{SiCl}_2$  with increasing  $T_{\text{dep}}$ . Especially at  $T_{\text{dep}} = 1600 \text{ K}$ , the summation of the partial pressure of the gases containing silicon in the gas phase is smaller than at other

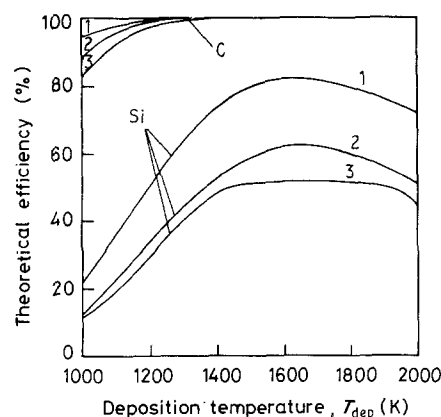


Figure 7 Effect of  $T_{\text{dep}}$  on theoretical efficiencies for carbon and silicon ( $P_{\text{tot}} = 40 \text{ kPa}$ ).  $m_{\text{Si/C}}$ : 1, 0.28; 2, 1.1; 3, 1.9.

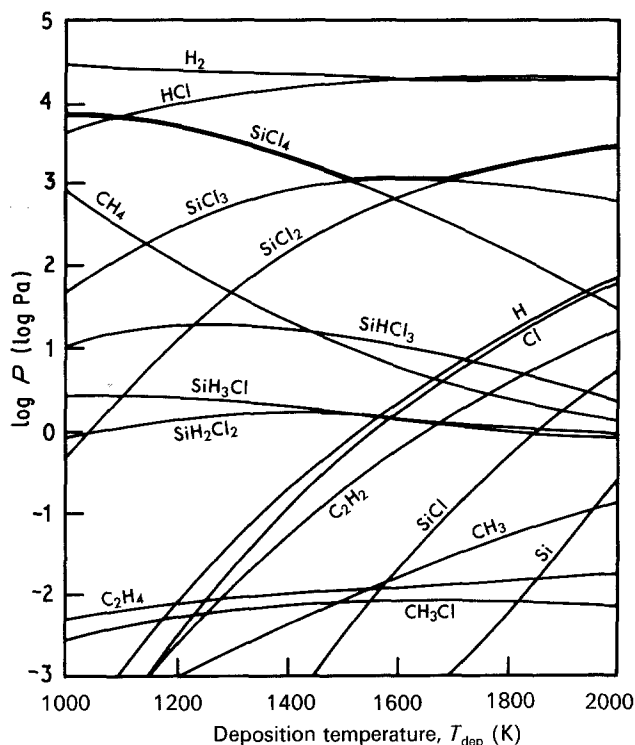


Figure 8 Relationship between  $T_{\text{dep}}$  and equilibrium partial pressures ( $P_{\text{tot}} = 40 \text{ kPa}$ ,  $m_{\text{Si/C}} = 1.1$ ).

temperatures, due to the relationship  $P_{\text{SiCl}_3} > P_{\text{SiCl}_4}$  and  $P_{\text{SiCl}_2}$  indicated by the bold line in Fig. 8. The facts that the theoretical efficiency of silicon is maximum around  $T_{\text{dep}} = 1600 \text{ K}$  as shown in Fig. 7 and that  $T_{\text{dep}} = 1600 \text{ K}$  is most suitable for controlling the composition of SiC-C as shown in Fig. 3, are the results of the  $T_{\text{dep}}$  dependency of the equilibrium partial pressure of gases containing silicon.

### 3.2. Morphology of CVD SiC-C

The morphology of CVD SiC-C prepared by the present work can be divided into two types: “dense-plate” and “porous”. Figs 9 and 10 represent typical scanning electron micrographs of the dense-plate and porous deposits, respectively. The deposition conditions ( $T_{\text{dep}}$  and  $P_{\text{tot}}$ ) and the composition of the deposits determine whether the deposits are dense-plate or porous as indicated by Fig. 11.

The dense-plate region can be extended by decreasing the amount of dispersed phase (i.e. near 0% and 100% on the horizontal axis in Fig. 11), and by increasing  $P_{\text{tot}}$ . We have previously reported a similar increase in

the dense-plate deposition region with increasing  $P_{\text{tot}}$  in the morphology of CVD SiC [11].

It is generally known that the morphology of CVD materials is affected by the degree of supersaturation of the source gases. The degree of supersaturation is defined by Equation 2 [17].

$$\Sigma_i = \frac{nP^{\text{in}}(i)}{\Sigma_j n_j P_j^{\text{eq}}(i)} \quad (2)$$

where  $\Sigma_i$  is the degree of supersaturation of atom  $i$ ,  $P^{\text{in}}(i)$  is the partial pressure of the source gas containing atom  $i$ ,  $P_j^{\text{eq}}(i)$  is the equilibrium partial pressure of gas species containing atom  $i$  ( $j$  represents the gas species, i.e.  $\text{SiCl}_4$ ,  $\text{SiCl}_3$ ,  $\text{SiCl}_2$ ,  $\text{CH}_4$ ,  $\text{C}_2\text{H}_2$  etc.),  $n$  and  $n_j$  are the number of atoms  $i$  contained in the gas species.

Fig. 12 shows the relationship between the equilibrium partial pressure of the gas species and  $P_{\text{tot}}$  at  $T_{\text{dep}} = 1673 \text{ K}$ ,  $m_{\text{Si/C}} = 1.1$ . The partial pressures of  $\text{SiCl}_4$ ,  $\text{C}_3\text{H}_8$  and  $\text{H}_2$  in the source gases are also indicated by broken lines in Fig. 12. The degrees of supersaturation of silicon and carbon were calculated from Equation 2 using the values of partial pressure in

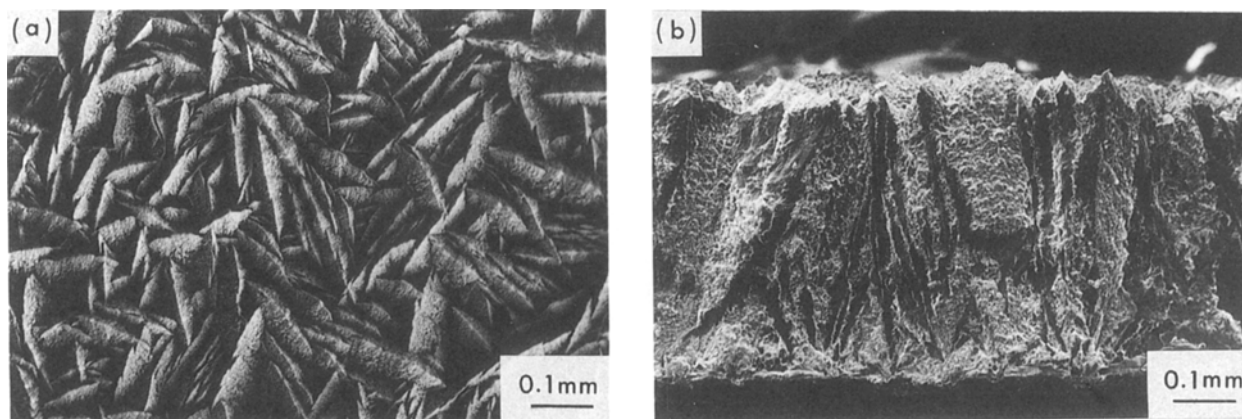


Figure 9 Scanning electron micrographs of the “dense-plate” deposit (SiC-38.9 mol % C) prepared at  $T_{\text{dep}} = 1673 \text{ K}$  and  $P_{\text{tot}} = 6.7 \text{ kPa}$ : (a) deposited surface, (b) cross-sectional surface.

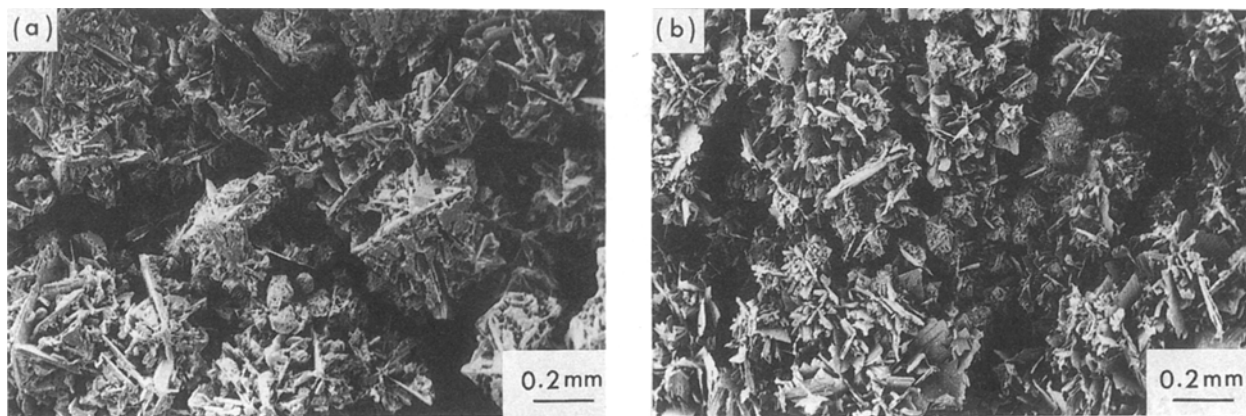


Figure 10 Scanning electron micrographs of the “porous” deposit (SiC–41.1 mol % C) prepared at  $T_{\text{dep}} = 1773 \text{ K}$  and  $P_{\text{tot}} = 13.3 \text{ kPa}$ : (a) deposited surface, (b) cross-sectional surface.

Fig. 12. Fig. 13 shows the relationship between supersaturation and  $P_{\text{tot}}$ . Both  $\Sigma_{\text{Si}}$  and  $\Sigma_{\text{C}}$  decreased with increasing  $P_{\text{tot}}$ . The same tendency was reported by Kim *et al.* in a Ti–C system [18].

It is said that particle formation takes places more easily with increasing supersaturation [19] resulting from homogenous reactions in the gas phase. Therefore, the possibility of having greater particle formation in the present work will increase with decreasing  $P_{\text{tot}}$ , as shown in Fig. 13.

Earlier reports shows that porous deposits of CVD  $\text{TiB}_2$  [20] and CVD TiC [21] have been formed depending on the deposition conditions. This porous structure was explained as the effect of particles partially adhering to the substrate and acting as abnormal nucleation-growth sites, and eventually some voids will result in the deposits. In this respect, the morphology of the deposits, as seen in the present work, became porous with decreasing  $P_{\text{tot}}$  as a consequence of particle formation. Fig. 11 also shows that the morphology of deposits became porous with increasing  $T_{\text{dep}}$ . This trend agrees well with many results generally known for CVD materials [19].

### 3.3. Deposition rate of CVD SiC–C

Fig. 14 shows the effect of  $m_{\text{Si/C}}$  on the growth rate by thickness of CVD SiC–C at  $T_{\text{dep}} = 1673 \text{ K}$ . The growth rate varied from 0.05 to 1.3  $\text{mm h}^{-1}$  depending on  $P_{\text{tot}}$  and  $m_{\text{Si/C}}$ . Deposition rates for SiC and carbon by weight were calculated using the growth rates, densities and compositions of CVD SiC–C as shown

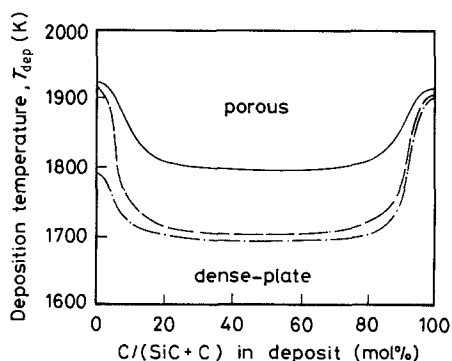


Figure 11 Relationship between morphology,  $T_{\text{dep}}$  and compositions.  $P_{\text{tot}}$  (kPa): (—) 40; (---) 13.3; (— · —) 6.7.

in Fig. 15a. The thermodynamically calculated deposition rates are also shown in Fig. 15b for comparison. The experimentally obtained relationship between the  $m_{\text{Si/C}}$  and deposition rates (Fig. 15a) is almost in agreement with that of the calculations (Fig. 15b). However, a maximum peak appears in the experimental deposition rate of carbon at  $m_{\text{Si/C}} = 0.28$ . This peak is a result of the small amount of  $\text{SiCl}_4$  vapour accelerating the deposition of carbon as mentioned in an earlier section.

Fig. 15a seems to indicate a maximum for the deposition rate of SiC at  $m_{\text{Si/C}} = 1.4$ . It has been reported that a small amount of free carbon can accelerate the deposition of SiC [11]. The present study confirms this finding.

A comparison of Figs 15a and b indicates that the deposition efficiency is about 20% for both SiC and carbon. The deposition efficiency is defined by the ratio of experimental deposition rate (Fig. 15a) and the calculated rate (Fig. 15b). This value is larger than that reported in many CVD materials whose value is ordinarily of the order of several per cent [22]. The

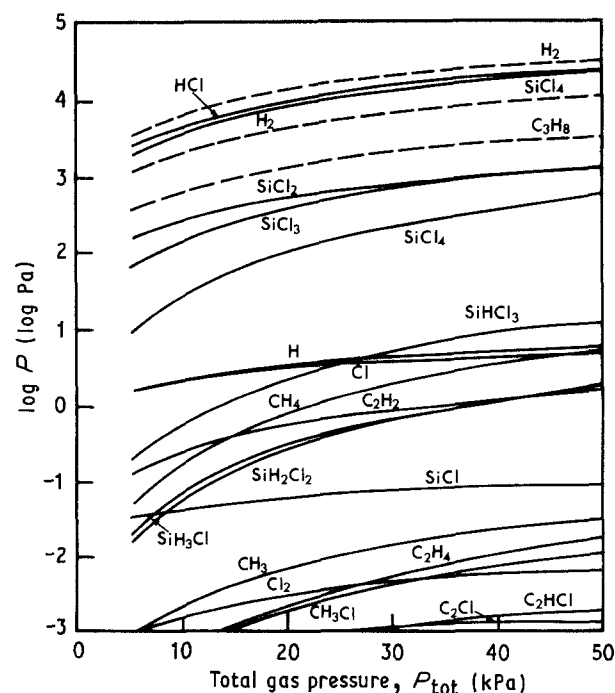


Figure 12 Effect of  $P_{\text{tot}}$  on equilibrium partial pressures ( $T_{\text{dep}} = 1673 \text{ K}$ ,  $m_{\text{Si/C}} = 1.1$ ).

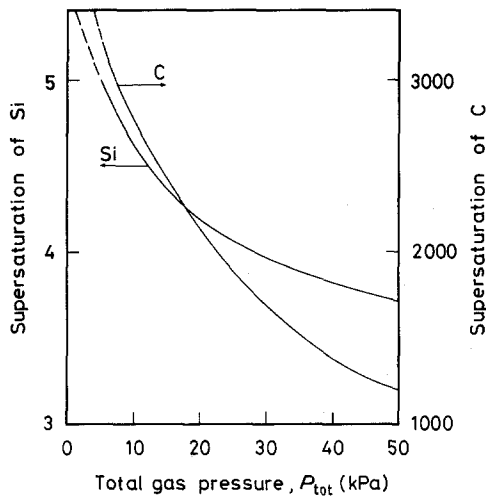


Figure 13 Effect of  $P_{\text{tot}}$  on supersaturation ( $T_{\text{dep}} = 1673 \text{ K}$ ,  $m_{\text{Si/C}} = 1.1$ ).

particular type of CVD reactor used in the present work may contribute to the improvement of the deposition efficiency. The cold-wall type used in the present study prevents premature reactions as well as deposition on the reactor-walls.

#### 4. Conclusions

SiC-C nano-composites covering the entire composition range from carbon to SiC were prepared by CVD using the  $\text{SiCl}_4\text{-C}_3\text{H}_8\text{-H}_2$  system. In order to show the optimum deposition conditions the thermodynamic calculations were compared with the experiments. The following results were obtained.

1. The preparation of SiC-C nano-composites at all compositions is thermodynamically feasible at  $m_{\text{Si/C}} = 0$  to 2.8 and  $T_{\text{dep}} = 1400$  to 2000 K. The calculation predicted the optimum  $T_{\text{dep}}$  to be about 1600 K.

2. The composition of SiC-C nano-composites was accomplished over all ranges at  $T_{\text{dep}} = 1673$  to 1873 K. The characteristics of the experimentally obtained compositions were in good agreement with the thermodynamic calculations.

3. The morphology of SiC-C nano-composites was of two types: dense-plate and porous. The dense-plate

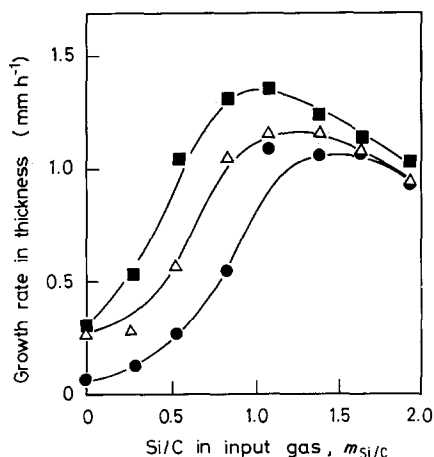


Figure 14 Relationship between growth rate of thickness and  $m_{\text{Si/C}}$  ( $T_{\text{dep}} = 1673 \text{ K}$ ).  $P_{\text{tot}}$  (kPa): (●) 6.7; (△) 13.3; (■) 40.

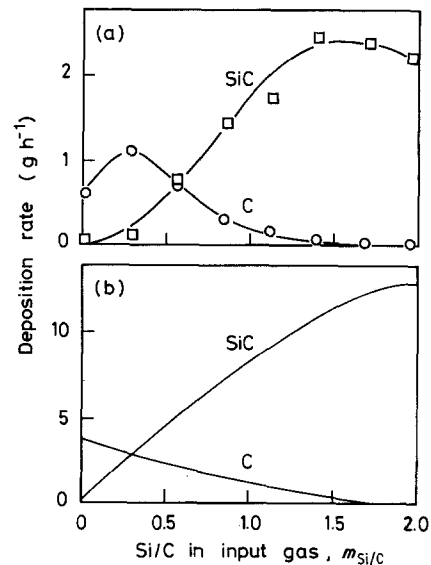


Figure 15 Relationship between deposition rate and  $m_{\text{Si/C}}$  ( $T_{\text{dep}} = 1673 \text{ K}$ ,  $P_{\text{tot}} = 40 \text{ kPa}$ ). (a) Experimental, (b) calculated.

deposits were obtained at lower  $T_{\text{dep}}$  and higher  $P_{\text{tot}}$ . The effect of  $P_{\text{tot}}$  on the morphology was explained by variation in the degree of supersaturation.

4. The relationship between  $m_{\text{Si/C}}$  and deposition rate was almost in agreement with the calculations. A large deviation from the calculation was observed in carbon-rich composites. The reason for this deviation was explained by the effect of  $\text{SiCl}_4$  vapour accelerating the deposition of carbon.

5. The deposition efficiencies of SiC and carbon were about 20%. This value is higher than typically reported values. The cold-wall type CVD reactor might have contributed the high efficiency in the present study. A cold-wall type reactor tends to prevent the premature reactions and deposition on the walls.

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